

FCC ID: 2A023-BTSP03

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	1.50	1.41	2.5±1	3.5	2.24	<5	0.69393	3.00	YES
	2.441	2.62	1.83	2.5±1	3.5	2.24	<5	0.69954	3.00	YES
	2.480	3.18	2.08	2.5±1	3.5	2.24	<5	0.70511	3.00	YES
π/4-DQPSK	2.402	1.51	1.42	2.4±1	3.4	2.19	<5	0.67814	3.00	YES
	2.441	2.44	1.75	2.4±1	3.4	2.19	<5	0.68362	3.00	YES
	2.480	2.38	1.73	2.4±1	3.4	2.19	<5	0.68906	3.00	YES
8DPSK	2.402	1.74	1.49	1.6±1	2.6	1.82	<5	0.56405	3.00	YES
	2.441	2.59	1.82	1.6±1	2.6	1.82	<5	0.56861	3.00	YES
	2.480	2.31	1.70	1.6±1	2.6	1.82	<5	0.57313	3.00	YES
BLE	2.402	1.69	1.48	2±1	3	2.00	<5	0.61847	3.00	YES
	2.44	2.24	1.67	2±1	3	2.00	<5	0.62334	3.00	YES
	2.48	1.69	1.48	2±1	3	2.00	<5	0.62843	3.00	YES

Conclusion:

For the max result : 0.70511W/Kg ≤ 3.0 for 1g SAR, No SAR is required.

Jason chen

Signature:

Date: 2018-03-15

NAME AND TITLE (Please print or type): Jason Chen /Manager

COMPANY (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen P.R. China.